METALLURGICAL MICROSCOPES

XJP-405

XJP-405 industrial microscope is equipped with a large moving range mechanical stage, Epi-illuminator, long working distance bright and dark field Infinite Plan objectives, wide field eyepiece with clear images and good contrast. It is developed and aimed at the semiconductor industry, wafer manufacturing, electronic in formation industry, metallurgical industry, and used as high grade industrial microscope. Bright & Dark field observation, EPI-polarizing and DIC observation can proceed. It is widely used in Factories, Research institution and college and Universities to identify and analyze Wafer, FPD, Circuit substrate, Precision moulds.

CHARACTERISTIC & DESCRIPTION

Adopt UIS high-resolution, long working distance, and infinity light path correcting system objective imaging technology
Extending the multiplexing technology of objective, compatible infinityobjective with all the observation methods. including bright & dark field observation, polarization and also provide with high clear and sharp image in each observation method.
Aspherical surface Kohler illumination, increasing the viewing brightness.
WF10 X（Φ25）super wide field eyepiece, long working distance metallurgical objective with bright and dark field
The nosepiece can be equipped with detachable DIC differential interference device.

Viewing Head	Compensation Free Trinocular Head, Inclined 30°（50mm-75mm）
Eyepiece	WF10X/25mm, WF10X/20mm,crosshair with reticule 0.1mm
Nosepiece	Quintuple Nosepiece with DIC Jack
Objective	Long working distance bright and dark field Infinite Plan objectives: 5X/0.1B.D/W.D.29.4mm, 10X/0.25B.D/W.D.16mm, 20X/0.40B.D/W.D.10.6mm, 40X/0.60B.D/W.D.5.4mm
Stage	Double layer mechanical stage, Stage Size: 350mmX310mm, Moving Range:250mmX250mm
Filter	Flashboard type filters(green,blue,neutral)
Focusing	Coaxial coarse & fine focusing adjustment With rack and pinion mechanism Fine focusing scale value 0.002mm
Light Source	Epi-illumination:With aperture iris diaphragm and field iris Diaphragm, Halogen Bulb 12V/100W, AC85V-230V, Brightness Adjustable
Polarizing Device	Analyzer rotatable 360°, Polariaer&Analyzer can be moved in/out of the optical path
Checking Tool	0.01mm Micrometer

XJL-301

XJL-301 reflected metallurgical microscope can be used for brightfield, darkfield, simple polarzing observations. It is the ideal instruments for inspecting semiconductors, packages, electronics substrates, materials.

Features:

1. With long working distance plan achromatic objectives (no cover glass) and wide-field eyepieces, can get clear pictures and wide view field
2. With large move range mechanical stages,moving range:8"X8"(204mmX204mm)
3. Coaxial coarse/fine focus system, with tensional adjustable and up stop, minimum division of fine focusing: 0.8μm
4. 6V 30W halogen lamp, adjustable brightnes
5. Trinocular, can switch to normally/polarize observation, brightfield/darkfield observation. can send
6. 100% of light to the binocular eyepieces or to the top port

Model	XJL-301
Eyepiece	Wide field WF10X/18mm
Objective	Long working distance plan achromatic objectives (BF) (no cover glass) PL 5X/0.12
	Long working distance plan achromatic objectives (BF / DF) (no cover glass)PL L10X/0.25 BD
	Long working distance plan achromatic objectives (BF / DF) (no cover glass) PL L20X/0.40 BD
	Long working distance plan achromatic objectives (BF / DF) (no cover glass) PL L40X/0.60 BD
Eyepieces tube	Trinocular, Inclination of 30˚, can send 100% of light to the binocular eyepieces or to the top port
Vertical illuminationn unit	6V 30W, halogen lamp, adjustable brightness
	Vertical illumination with field diaphragm, aperture diaphragm and polarizer, (Y,B,G)filter and Ground glass
Focus system	Stage adjustable, Coaxial coarse/fine focus system, with tension adjustable and limit stopper, minimum division of fine focusing:0.8μm.
Nosepiece	Quadruple (Frontward ball bearing inner locating)
Stage	Three layer mechanical,Size:280mmX270mm,moving range:8"X8" (204mmX204mm)

XJP-607

XJP-607 Industrial Metallurgical microscope is developed and aimed at the semiconductor industry, wafer manufacturing, electronic information industry, metallurgical industry. Used as an advanced Metallurgical microscope, the user can experience its super performance when using it.It can be widely used to identify and analyze Semiconductor, FPD, Circuit encapsulation, circuit substrate, Material, Casting/Metal/Ceramic parts, Precision moulds and observe thicker specimen. High quality and reliable optical system brings much clearer and contrast image. The design meets with the ergonomics needs and makes you feel comfortable and relaxed in doing your job.

Characteristicsand description

1. UIS infinite-optical system.
2. Adopt long-life halogen light source with much higher light efficiency.
3. Bright and dark field, Polarization and differential interference function.
4. The aspherical Kohler illumination, increasing the brightness of observation.
5. WF10X/Φ25 super wide viewing field eyepiece, long working distance metallurgical objective with bright and dark field
6. The Quintuple Nosepiece can be equipped with detachable DIC differential interference device.

DIC: Nomarski differential interference contrast observation is deemed to the essential means to checkout the materials, semiconductor and metal structure now.

Viewing Head	Compensation Free Trinocular Head, Inclined 30˚（50mm-75mm）
Eyepiece	WF10X/25mm, WF10X/20mm,crosshair with reticule 0.1mm
Objective	Long working distance bright and dark field Infinite plan objectives: 5X/0.1 B.D/W.D.29.4mm, 10X/0.25B.D/W.D.16mm, 20X/0.40B.D/W.D.10.6mm, 40 X/0.60B.D/W.D.5.4mm
Nosepiece	Quintuple Nosepiece with DIC Jack
Stage	Double layer mechanical stage, Stage Size: 190mmX140mm, Moving Range:50mmX40mm
Filter	Flashboard type filters(green,blue,neutral)
Focusing	Coaxial coarse ＆fine focusing adjustment With rack and pinion mechanism Fine focusing scale value 0.002mm
Light Source	With aperture iris diaphragm and field iris diaphragm, halogen Bulb 12V/50W, AC85V-230 Brightness Adjustable
Polarizing Device	Analyzer rotatable 360˚, Polarizer＆Analyzer can be moved in/out of the optical path
Checking Tool	0.01mm Micrometer

XJP-607A

Micrometer Eyepiece

XJP-607 Industrial Metallurgical microscope is developed and aimed at the semiconductor industry, wafer manufacturing, electronic information industry, metallurgical industry. Used as an advanced Metallurgical microscope, the user can experience its super performance when using it.It can be widely used to identify and analyze Semiconductor, FPD, Circuit encapsulation, circuit substrate, Material, Casting/Metal/Ceramic parts, Precision moulds and observe thicker specimen. High quality and reliable optical system brings much clearer and contrast image. The design meets with the ergonomics needs and makes you feel comfortable and relaxed in doing your job.

Characteristicsand description

Adopt UIS High-resolution, Long working distance, and infinity light path correcting system objective imaging technology.
Extending the multiplexing technology of objective, compatible infinity objective with all the observation methods.
Aspherical surface Kohler illumination, increasing the viewing brightness.
WF10X/Φ25 super wide viewing field Eyepiece.

Viewing Head	Compensation Free Trinocular Head, Inclined 30°（50mm-75mm）
Eyepiece	WF10X/25mm, WF10X/20mm,crosshair with reticule 0.1mm
Objective	Long working distance Infinite Plan Apochromatic objectives: 5X/0.15/W.D.35mm, 10X/0.28/W.D.35mm, 20X/0.40/W.D.20mm, 50X/0.55/W.D.13mm
Nosepiece	Quadruple nosepiece with center adjustable
Stage	Double layer mechanical stage, Stage Size: 190mmX140mm, Moving Range:50mmX40mm
Filter	Flashboard type Filters:(green,blue,neutral)
Focusing	Coaxial coarse & fine focusing adjustment with rack and pinion mechanism. Fine focusing scale value 0.002mm
Light Source	With aperture iris diaphragm and field iris diaphragm,halogen bulb 12V/50W, AC 85V-230V, brightness adjustable
Polarizing Device	Analyzer rotatable 360°, Polarizer&Analyzer can be moved in/out of the optical path
Checking Tool	0.01mm Micrometer

Micrometer Eyepiece is accessory for a variety of optical measuring instruments ,when assembled on an appropriate optical instrument, it can be used for various measurements, such as measuring the holes′distance, width and length of the graduation scale and keyways, metal surface quality, spectrum bandwidth, the density of fiber fabric and the field specimens and so on, it can also measure the size of indentation and scratch as accessory of some micro hardness tester.

XJL-101 201 SERIES

XJP-101

XJP-201

XJL-101 201 series reflected metallurgical microscopes are suitable to observe the microscopical surfaces of non-transparent object. They are equipped with large move range mechanical stages, reflected vertical illumination and set polarizer device in trinocular. They have clear and high-contrast picture beautiful sculpt, convenient control and etc. they are the ideal instrument in research work in metallography,mineralogy, precision engineering, electronics and etc. They are suitable for scientific research, teaching demonstration in the colleges and factory.

Features:

1. With plan achromatic objectives with long working distance (no cover glass) and wide-field eyepieces, can get clear pictures and wide view field.
2. With large move range mechanical stages, can move quickly and slowly.
3. Coaxial coarse/fine focus system, with tension adjustable and up stop, minimum division of fine focusing: 0.7μm.
4. 6V 20W halogen lamp, adjustable brightness.
5. Trinocular, can switch to observe normally or to observe the polarize, can send 100% of light to the binocular eyepieces or to the top port.

Model	XJL-101, XJL-201	XJL-101A, XJL-201A
Eyepiece	Wide field WF10X/18mm	
Objective	Plan achromatic objectives with long working distance (no cover glass) PL 5X/0.12	
	Plan achromatic objectives with long working distance (no cover glass) PL L10X/0.25	
	Plan achromatic objectives with long working distance (no cover glass) PL L20X/0.40	
	Plan achromatic objectives with long working distance (no cover glass) PL L40X/0.60	
	Plan achromatic objectives with long working distance (no cover glass) PL L80X/0.80	
Eyepieces tube	Trinocular, Inclination of 30˚, (Analyzer with field diaphragm to switch)	
Vertical illumination unit	6V 20w, halogen lamp, adjustable brightness	
	Vertical illumination with field diaphragm, aperture diaphragm and polarizer,(Y,B,G)filter and frosted filter	
Focus system	Vertical adjustable, Coaxial coarse/fine focus system, with tensional adjustable and up stop, minimum division of fine focusing2μm.	
Nosepiece	Quintuple (Frontward ball bearing inner locating)	
Stage	Three layer mechanical, Size:250mmX230mm, movingrange:154mmX154mm	Three layer mechanical Size:280mmX270mm, movingrange:204mmX204mm

L2003

L2003 series reflected metallurgical microscopes are suitable to observe the surfaces of non-transparent object. They are equipped with vertical illuminator, plan achromatic objectives with long working distance (no cover glass), wide-field eyepieces and set polarizer device in trinocular. They provide clear and high-contrast picture, convenient operation and etc. They are the ideal instruments for research work in metallography, mineralogy, precision engineering, electronics and etc. They are suitable for scientific research, teaching demonstration in the colleges and factory.

Model	L2003A	L2003B
Eyepiece	Wide field WF10X/18mm	
Objective	Plan achromatic objectives with long working distance (no cover glass) PL 5X/0.12	
	Plan achromatic objectives with long working distance (no cover glass) PL L10X/0.25	
	Plan achromatic objectives with long working distance (no cover glass) PL L40X/0.60	
	Plan achromatic objectives with long working distance (no cover glass) PL L60X/0.75 (Spring)	
		Plan achromatic objectives with long working distance (no cover glass) PL L20X/0.40
Eyepieces tube	Trinocular,Inclination of 30˚, (Analyzer with field diaphragm to switch)	
Vertical illumination unit	6V 20W, Halogen lamp, adjustable control	
	Vertical illumination With field diaphragm ,aperture diaphragm and polarizer,(Y,B,G)filter and frosted filter	
Focus system	Coaxial coarse/fine focus system, with tensional adjustable and up stop, minimum division of fine focusing: 2μm.	
Nosepiece	Quadruple Backward ball bearing inner locating	Quintuple Backward ball bearing inner locating
Stage	Double layer mechanical (Size:185mmX140mm,movingrange:75mmX50mm)	

Optional accessories

Name	Sort/Technique parameter
Eyepiece	Wide field WF16X/11mm, Dividing 10X/8mm 0.1mm/Div
Objective	Plan achromatic objectives with long working distance (no cover glass) PL L50X/0.70, PL L80X/0.80, PL L100X/0.85 (S),
	Plan achromatic objectives (no cover glass) PL 100X/1.25(S, oil)
CCD adapter	0.4X, 0.5X, 1X, 0.5X with dividing 0.1mm/Div
Photo unit	2.5X/4X Change over photograph attachment with 10X viewing eyepiece, 4X Focusing photograph attachment, MD Adapter, PK Adapter

L3003

L3003 reflected metallurgical microscope is suitable to observe the surfaces of non-transparent object. It is equipped with vertical illuminator, plan achromatic objectives with long working distance (no cover glass), wide-field eyepieces and set polarizer device in trinocular. It provide clear and high-contrast picture, beautiful sculpt, convenient operation, etc. It is the ideal instruments for research work in metallography, mineralogy, precision engineering, electronics, etc. It is suitable for scientific research, teaching demonstration in the colleges and factory.

Model	L3003
Eyepiece	Wide field WF10X/18mm
Objective	Plan achromatic objectives with long working distance (no cover glass) PL 5X/0.12
	Plan achromatic objectives with long working distance (no cover glass) PL L10X/0.25
	Plan achromatic objectives with long working distance (no cover glass) PL L20X/0.40
	Plan achromatic objectives with long working distance (no cover glass) PL L50X/0.70
Eyepieces tube	Trinocular,Inclination of 30˚, (Analyzer with field diaphragm to switch)
Vertical illumination unit	6V 20W, Halogen lamp,Adjustable brightness
	Vertical illumination With field diaphragm, aperture diaphragm and polarizer, (Y, B, G) filter and Ground glass
Focus system	Coaxial coarse/fine focus system, with tension adjustable and up stop, min division of fine focusing: 2μm
Nosepiece	Quadruple Backward ball bearing inner locating
Stage	Double layer mechanical (Size: 210mmX140mm,movingrange:75mmX50mm)

Optional accessories

Name	Sort/Technique parameter
Eyepiece	Wide field WF16X/11mm, Dividing 10X/8mm 0.1mm/Div
Objective	Plan achromatic objectives with long working distance (no cover glass) PL L40X/0.60, PL L60X/0.75 (S), PL L80X/0.80, PL L100X/0.85 (S)
	Plan achromatic objectives (no cover glass) PL 100X/1.25(S, oil)
Nosepiece	Quintuple Backward ball bearing inner locating
CCD adapter	0.4X, 0.5X, 1X, 0.5X with dividing 0.1mm/Div
Photo unit	2.5X/4X Change over photograph attachment with 10X viewing eyepiece, 4X Focusing photograph attachment, MD Adapter, PK Adapter

L3030

L3030 reflected and transmitted microscope is suitable to observe surfaces of non-transparent object or transparent object. It is equipped with vertical illuminator, plan achromatic objectives with long working distance (no cover glass), wide-field eyepieces and set polarizer device in trinocular. It provide clear and high-contrast image, beautiful sculpt,convenient control, etc. It is the ideal instruments in research work in biology, metallography, mineralogy, precision engineering, electronics, etc. It is suitable for scientific research, teaching demonstration in the colleges and factory.

Features:

1. With plan achromatic objectives with long working distance (no cover glass) and wide-field eyepieces, can get clear pictures and wide view field.
2. Coaxial coarse/fine focus system, with tensional adjustable and up stop, minimum division of fine focusing: 2μm.
3. With vertical illuminator and transmitted illuminator, can observe surfaces of non-transparent object or transparent object.
4. 6V 20W halogen lamp, adjustable brightness.
5. Trinocular, can switch to observe normally or to observe the Polarize, can send 100% of light to the binocular eyepieces or to the top port.

Model	L3030
Eyepiece	Wide field WF10X/18mm
Objective	Plan achromatic objectives with long working distance (no cover glass) PL 5X/0.12, PL L10X/0.25, PL L20X/0.40, PL L50X/0.70
Eyepieces tube	Trinocular, Inclination of 30˚, (Analyzer with field diaphragm to switch)
Vertical illumination unit	6V 20W, halogen lamp, adjustable brightness
	Vertical illumination with field diaphragm, aperture diaphragm and polarizer,(Y,B,G)filter and Ground glass
Focus system	Coaxial coarse/fine focus system, with tension adjustable and up stop, min division of fine focusing: 2μm.
Nosepiece	Quadruple(Backward ball bearing inner locating)
Stage	Double layer mechanical (Size:210mmX140mm,movingrange:75mmX50mm)
Transmitted illumination unit	Abbe condenser NA.1.25 Rack & pinion adjustable, Blue filter and Ground glass
	Collector for illumination with halogen lamp (With field diaphragm)
	6V 20W, halogen lamp, adjustable brightness

XJP-158J

XJP-158J Metallurgical microscope is developed and aimed at the semiconductor industry, wafer manufacturing, electronic information industry, metallurgical industry, Used as an advanced Metallurgical microscope, the user can experience its super performance when using it. It can be widely used to identify and analyze Semiconductor, FPD, Circuit encapsulation, circuit substrate, Material, Casting/Metal/Ceramic parts, Precision moulds. This instrument adopts both reflecting and transmitted illumination, Bright＆Dark field, DIC and Polarizing observation can proceed under reflecting illumination, and the Bright field observation is done under transmitted light. High quality and reliable optical system brings much clearer and sharper image. The design meets with the ergonomics needs and makes you feel comfortable and relaxed in doing your job.

CHARACTERISTIC & DESCRIPTION

Adopt UIS High-resolution, long working distance, and infinity light path correcting system objective imaging technology

Extending the multiplexing technology of objective, compatible infinity objective with all the observation methods, including bright＆dark field observation, polarization and DIC also provide with high clear and sharp image in each observation method.

Aspherical surface Kohler illumination, increasing the viewing brightness.

WF10X/Φ25 super wide viewing field eyepiece, long working distance metallurgical objective with bright and dark field

The Nosepiece can be equipped with detachable DIC differential interference device.

Viewing Head	Compensation Free Trinocular Head, Inclined 30˚（50mm-75mm）
Eyepiece	WF10X/25mm, WF10X/20mm,crosshair with reticule 0.1mm
Objective	Long working distance bright＆dark field Infinity. Plan Objectives: 5X/0.1B.D/W.D.29.4mm, 10X/0.25B.D/W.D.16mm, 20X/0.40B.D/W.D.10.6mm, 40X/0.60B.D/W.D.5.4mm
Nosepiece	With DIC Jack Quadruple Nosepiece
Stage	Double layer mechanical stage, Stage Size: 189mmX160mm, Moving Range:80mmX50mm
Filter	Flashboard type Filters (green, blue, neutral)
Condenser	N.A.1.25 Abbe Condenser with iris diaphragm and filter
Focusing	Coaxial coarse＆fine focusing adjustment with rack and pinion mechanism. Fine focus scale value 0.002mm
Light Source	Transmission Illumination: Halogen Bulb 12V/50W,AC85V-230V, Brightness Adjustable
	Epi-illumination:With aperture iris diaphragm and field iris diaphragm, halogen Bulb 12V/50W, AC85V-230V, Brightness Adjustable
Polarizing	Analyzer 360˚rotatable,both Polarizer and Analyzer can be moved out of the light path
Checking Tool	0.01mm Micrometer

XJP-146JB

This equipment can be used in observation, analysis and research of Metallurgy, Mineral, Crystal, Micro-electronics and it is the first choice for the factories, universities, research institutions and electronic industry. It is adopted 2 kinds of illumination of reflection and transmission and also equipped with Epi-illumination Polarization devices. Under the reflected light, it can proceed Bright field and Polarizing observation. And it can also proceed Bright field observation under transmitted illumination. Stable, high-quality optical systems meet your requirement of high image quality, square-built body represents more rigid, T-shaped design gives you a more stable base. Humanized configuration design and convenient operation, Let you release form the pressure of heavy work. Let you devote experiment with entire energy.

Specification		146JB	146JBT
Viewing Head	Compensation Free Binocular Head Inclined at 30˚(55mm-75mm)	*	
	Compensation Free Trinocular Head Inclined at 30˚(55mm-75mm)		*
Eyepiece	WF10X/22mm, WF10X/20mm crosshair with reticule 0.1mm	*	*
Nosepiece	Quadruple nosepiece	*	*
Objective	Infinity plan metallurgical objective, 4X/0.1W.D.29.4mm, 10X/0.25W.D.16mm, 20X/0.4 W.D.10.6mm, 40X/0.6W.D.5.4mm	*	*
Stage	Double layer mechanical stage, Stage Size: 180mmX150mm, Moving Range: 75mm X 50mm	*	*
Focusing	Coaxial coarse &fine focusing adjustment with rack and pinion mechanism. Fine focusing scale value 0.002mm	*	*
Condenser	N.A.1.25 Abbe Condenser with irisdiaphragm&filter	*	*
Light Source	Epi-Kohler illumination with aperture iris diaphragm and Field iris diaphragm	*	*
	Transmission illumination 12V/30W.AC85V230V Adjustable Brightness	*	*
Polarizing Device	Analyzer rotatable360˚polarizer&analyzer can be moved in/out of the optical path	*	*
Filter	Flashboard type filters(green ,blue neutral)	*	*
Checking Tool	0.01mm Micrometer	*	*

XJP-146J SERIES

Model XJP-146J series Up-right Metallurgical Microscope used in observation & analysis of metallurgy, Mineralogy, crystal and micro-electronics, etc. It is the first choice of Factories, Universities, Scientific research organization and Electronic industrial department. It adopts 2 kinds of illumination, reflection and transmission and epi-polarizing fitting is also outfitted. You can proceed not only Bright field and Polarizing viewing under illumination of reflection light, but also making bright field viewing under transmission light. Stable and superior optical system meet your high quality image requirement. "T" type figure design provides the stable base, humanized configuration design, simple and convenient operating system make your work easy and relax.

Specification		146J	146JT	146JA	146JAT
Viewing head	Compensation Free Binocular Head. Inclined at 30˚ (55mm -75mm)	*		*	
	Compensation Free Trinocular Head. Inclined at 30˚ (55mm -75mm)		*		*
Eyepiece	WF10 X /20mm	*	*		
	WF10 X/ 22mm			*	*
	WF10 X/ 20mm with reticule 0.1mm		*		*
Nosepiece	Quadruple nosepiece	*	*	*	*
Objective	195 metallurgical objectives 4X0.1W.D .25mm, 10X 0.25W.D .11mm, 20X 0.4W.D .9mm 40X 0.6W.D. 3.8mm	*	*		
	Infinity metallurgical objectives: 4X0.1WD.25mm, 10X0.25WD11mm, 20X 0.4W.D .8mm, 40X 0.6W.D. 3.8mm			*	*
Stage	Double layers mechanical stage, Stage size: 180mm X 150mm, Moving range: 75mm X 50mm	*	*	*	*
Condenser	N.A1.25 Abbe condenser with iris diaphragm & filter	*	*	*	*
Focusing	Coaxial coarse&fine focusing adjustment with rack and pinion mechanism Fine focusing scale Value 0.002mm	*	*	*	*
Illumination	Epi-Kohler illumination. with aperture iris diaphragm and field iris diaphragm transmission light, 12V/30W. AC85V-230V adjustable brightness	*	*	*	*
Polarizing outfit	Analyzer rotatable 360˚, polarizer & analyzer can be slided slided in / out of the optical path	*	*	*	*
Filter	Blue, green, yellow	*	*	*	*
Checking tool	0.01mm micrometer	*	*	*	*

XJP-408

XJP-408 Up-right Metallurgical Microscope is applicable to the observation of transparent and opaque objects. It is equipped with Epi-illumination, transmission illumination system, plan achromatic objectives with sharp & clear image and good contrast. In the meanwhile, it is eguiped with polarizing device, it´s an ideal instrument for research such as Metallographic, Precision Engineering and Electronics, suitable for School, Scientific research department and factories as well.

Specification		Model	
		XJP-408	XJP-408T
Viewing Head	Compensation Free Binocular Head Inclined at 30˚ (50mm-75mm)	*	
	Compensation Free Trinocular Head Inclined at 30˚ (55mm-75mm)		*
Eyepiece	WF10X/18mm, WF10X/18mm, crosshair with reticule 0.1mm	*	*
Nosepiece	Quadruple nosepiece	*	*
Objective	DIN Plan Metallurgical objectives: 4X/0.1W.D.25mm, 10X/0.25W.D.11mm, 20X/0.4W.D.9mm, 40X/0.6W.D.3.8mm	*	*
Stage	Double layer mechanical stage, Stage Size: 140mmX140mm, Moving Range: 75mmX50mm	*	*
Filter	Inserting type filter(green, blue, Yellow)	*	*
Focusing	Coaxial coarse & fine focusing adjustment mechanism, Fine focusing scale value 0.002mm	*	*
Illuminator	N.A.1.25 Abbe condenser with iris diaphragm and filter	*	*
Light Source	Epi-illumination: Halogen Bulb 6V/20W, AC85V-230V,Adjustable brightness	*	*
	Transmission illumination: Halogen Bulb 6V/20W, AC85V-230V, Adjustable brightness	*	*
Polarizing Device	Analyzer 360˚ rotatable, both Polarizer and Analyzer can be moved out of the light path	*	*
Checking Tool	0.01mm Micrometer	*	*

XJP-407

XJP-407 Inverted Metallurgical Microscope is widely used in metallurgical structure analysis for Mechanical industry and Mineral research analysis of geology mineral resources department, and observation & measuring of Crystal, Integrated Circuits, Microelectronics of electronic industry. It´s also the first choice for the factories, colleges & universities, scientific institution and electronic industry. High quality and reliable optical system bring s much clearer and contrast image. Novel and simplified figure craftsmanship keep abreast of times tidal current much more. Humanized configuration design and convenient operation, let you release from the pressure of heavy work.

Viewing Head	Compensation Free Trinocular Head, Inclined at 45˚
Eyepiece	WF10X/18mm
	WF10X/18mm, crosshair with reticule 0.1mm
Objective	DIN Plan Metallurgical objectives: 4X/0.1W.D.25mm, 10X/0.25W.D.11mm, 20X/0.4W.D.9mm, 40X/0.6W.D.3.8mm
Stage	Double layer mechanical stage, Stage Size: 172mmX142mm, Moving Range: 30mmX30mm
Filter	Inserting type filter(green, blue, Yellow)
Focusing	Coaxial coarse & fine focusing adjustment With rack and pinion mechanism Fine focusing scale value 0.002mm
Light Source	With aperture iris diaphragm and Field diaphragm, Halogen lamp 12V/20W, AC85V-230V, Adjustable Brightness
Polarizing Device	Analyzer rotatable 360˚, both Polarizer and Analyzer can be moved out of the ight path
Checking Tool	0.01mm Micrometer

XJP-403J SERIES

This series microscope is widely used in observation & analysis of metallurgical organization in Mechanical industry, Research of Geological & Mineral department and viewing & measuring crystal, integrate circuit, micro-electronics, etc in Electronic industry. It is the first choice of Factories, Academy, Scientific research organization contrast image. Novel figure and superior craftsmanship keep abreast of the tidal current much more.
Humanized configuration design and simple operation, Let you release from the pressure of heavy work.

Specification		403J	403JT	403JA	403JAT
Viewing head	Compensation Free Binocular Head. Inclined at 45˚ (50mm -75mm)	*		*	
	Compensation Free Trinocular Head. Inclined at 45˚ (50mm -75mm)		*		*
Eyepiece	WF10X 20mm	*	*		
	WF10X 22mm			*	*
	WF10X 20mm with reticule 0.1mm	*	*	*	*
Nosepiece	Quadruple nosepiece			*	*
	Quintuple nosepiece	*	*		
Objective	195 metallurgical objectives 4X/0.1W.D.25mm, 10X/0.25W.D.11mm, 20X/0.4W.D.9mm, 40X/0.6W.D.3.8mm	*	*		
	Infinity metallurgical objectives 4X0.1W.D.25mm, 10X0.25W.D.12mm, 20X 0.4W.D.10mm, 40X0.6W.D. 7.1mm			*	*
Stage	Double layers mechanical stage, Stage size: 242mmX172mm, Central stage: Φ110mm, Moving range: 75mm X 50mm	*	*	*	*
Focusing	Coaxial coarse&fine focusing adjustment with rack and pinion mechanism Fine focusing scale Value 0.002mm	*	*	*	*
Illumination	Epi-Kohler illumination. With aperture iris diaphragm and field iris diaphragm. 12V/30W. AC85V-230V Adjustable brightness	*	*	*	*
Filter	Blue, green, yellow	*	*	*	*
Polarizing outfit	Analyzer rotatable 360˚, polarizer & analyzer can be slided slided in / out of the optical path	*	*	*	*
Checking tool	0.01mm micrometer	*	*	*	*

XJP-401 SERIES

XJP-401A

XJP-401B

Specification				Model	
				XJP-401A	XJP-401B
Viewing Head	Monocular Inclined at 45˚			*	
	Compensation Free Binocular Head Inclined at 45˚(55mm-75mm)				*
Eyepiece	WF10X/18mm			*	
Semi-plan Achromatic Objective	Magnification	10X	100X		
	Numerical Aperture	0.25	1.25		
	System	Dry	Oil		
	Working Distance	7.31mm	0.37mm		
Semi-plan Achromatic Objective	Magnification	40X			
	Numerical Aperture	0.65			
	System	Dry			
	Working Distance	0.66mm			
Total Magnification	100X -1250X				
Mechanical tube Length	160mm				
Focusing	Coaxial coarse & fine focusing adjustment, Fine focusing scale value 0.002mm Focusing Range 30mm				
Working Stage	175mmX135mm				
Light Source	Halogen bulb 6V20W , AC 220V/110V				
Object plate	Φ100mm Φ20mm Φ42mm				

MDS200

Items	Specifications	MDS200
Eyepieces	WF10X /Φ18	**
	WF10X /Φ20	**
	WF12.5X /Φ14	**
	WF16X /Φ13	**
	Huygenian Eyepieces 5X/Φ20	**
	WF10X/(Reticule)	*
Plan Achromatic Objectives	Plan 2.5X/0.07	*
	Plan 4X/0.10	*
	Plan 10X/0.25	*
	Plan 20X/0.35 (S)	*
	Plan 40X/0.65 (S)	*
	Plan 100X/1.25 (S, Oil)	*
Trinocular Head	Inclined 45˚ Light Distribution:20:80	*
Mechanical Stage	Size: 180X165mm, Travel Range: 50X40mm	*
Stage Plate	1 (Φ10)	*
	2 (Φ20)	*
	3 (Φ40)	*
Set of Stage Plate		*
Main Body		*
Polarizing Slide		*
Analyzing Slide		*
Illuminator	6V/30W Halogen Lamp Spare Lamp: 2pcs, Spare Fuse: 2pcs	*
Filters	Blue, Green, Grey, White	*

XJL-17 SERIES

XJL-17 series metallurgical microscopes are used for identification and analysis of the structures in different metals and alloys. They are the important instruments for researching metallography in metal physics. The instruments can select special photography device to take euploid pictures of atlas metallograph. The instruments are suitable for scientific research, colleges and factory .

Features

1. With plan achromatic objectives with long working distance (no cover glass) and wide-field eyepieces, can get clear pictures and wide view field.
2. Coaxial coarse/fine focus system, with tension adjustable and up stop, minimum division of fine focusing: 2μm.
3. 6V 20W halogen lamp, brightness control.
4. Trinocular is compensation, can switch to observe normally or to observe the Polarize, can send 100% of light to top photography port.

Standard Configuration

Model	XJL-17AT	XJL-17BT
Eyepiece	Wide field WF10X/18mm	
Objective	Plan achromatic objectives with long working distance (no cover glass) PL 10X/0.25	Achromatic objectives(no cover glass) 10X/0.25
	Plan achromatic objectives with long working distance (no cover glass) PL L20X/0.40	Achromatic objectives(no cover glass) 20X/0.40
	Plan achromatic objectives with long working distance (no cover glass) PL L40X/0.60	Achromatic objectives(no cover glass) SP 40X/0.65
	Plan achromatic objectives with long working distance (no cover glass) PL 100X/1.25(S, oil)	Achromatic objectives(no cover glass) 100X/1.25(S, oil)
Eyepieces tube	Trinocular, Inclination of 30˚	
Filter	Frosted filter, Blue filter, Green filter, Yellow filter	
Focus system	Coaxial coarse/fine focus system, with tensional adjustable and up stop, minimum division of fine focusing: 2μm.	
Nosepiece	Quadruple(Ball bearing inner locating)	
Stage	Double layer mechanical (Size:180mmX150mm,moving range:15mmX15mm)	
Illumination unit	6V 20W halogen lamp, brightness control.	

YJ-2006 SERIES

YJ-2006B

YJ-2006M

SPECIFICATION		MODEL	
		2006B	2006M
Viewing head	Monocular Viewing Head		*
	Articulated Free Binocular Viewing Head，Interpuillary Adjustment From 50mm to 75mm, Diopter Adjustment On One Ocular Tube	*	
Eyepiece	Each Paired Of Wide-field Plano-Scope Eyepiece WF10X And WF12.5X，WF10X Wide-field Plano-scope Eyepiece With 0.1mm Cross Micrometer: 1pc	*	*
Objective	Achromatic Objective: 10X,100X(S, Oil) Metallurgical Plan-scope Achromatic Objectives: 40X(S)	*	*
Maginification	100X-1250X		
Stage	Double Layers Mechanical Stage 200X180mm, With Two Plates (Φ10 and Φ20mm), Moving In 50X70mm	*	*
Focusing	Coaxial Coarse And Fine Focusing Adjustable Mechanism By Rack And Pinion With Tension Adjustment And Stage Height Limited Knob: 25mm/0.002mm	*	*
Illumination	Built-in Continuous Adjustable Brightness Halogen Lamp 6V/20W, Kohlar Illumination With Blue, Green And Yellow Filter	*	*